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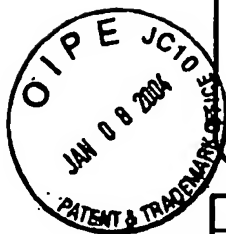
INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet **1** of **6**

Complete if Known

Application Number	10/600,224
Filing Date	6/20/2003
First Named Inventor	Bickford, Randall L.
Group Art Unit	2121
Examiner Name	Not yet Assigned
Attorney Docket Number	23404-cpa



U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
R/S	1	4,295,128		Hashemian et al.	10-13-1981	
	2	4,478,783		Broadwater	10-23-1984	
	3	4,761,748		Le Rat et al.	08-02-1988	
	4	4,937,763		Mott	06-26-1990	
	5	4,975,968		Yukl, Tex	12-04-1990	
	6	5,009,833		Takeuchi et al.	04-23-1991	
	7	5,223,207		Gross et al.	06-29-1993	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				

Examiner Signature	<i>Rancho Patel</i>	Date Considered	10/26/04
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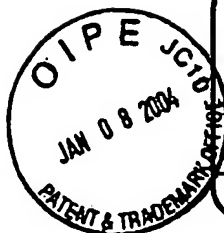
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Attorney Docket Number	23404-cpa

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Sheet 2 of 6

Attorney Docket Number	23404-cpa
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Ramesh Patel

10/26/04

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Sheet 3 of 6

Complete if Known

Application Number	
Filing Date	
First Named Inventor	Bickford, Randall L.
Group Art Unit	
Examiner Name	
Attorney Docket Number	23404-cpa

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
<i>RL</i>	35	BICKFORD, R.L., Phase Partitioning the Multivariate State Estimation Technique (MSET) Process for Improved Parameter Estimation Performance and Processing Speed, New Technology Report, January 13, 2000, Printed in USA by Expert Microsystems, Inc.	
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Ramesh Patel

Date
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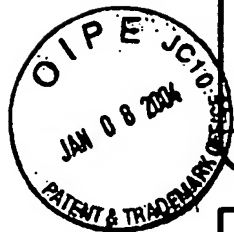
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Sheet 4

of 6

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Application Number

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First Named Inventor Bickford, Randall L.

Group Art Unit

Examiner Name

Attorney Docket Number 23404-cpa

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RB	46	BICKFORD, R.L., et al, Real-Time Space Shuttle Main Engine Sensor Validation, National Aeronautics and Space Administration, August 1995, Printed in USA by ExperTech & Intelligent Software Associates, Inc.	
✓	47	BICKFORD, R.L., et al, Real-Time Flight Data Validation For Rocket Engines, AIAA, 1996, Printed in USA by ExperTech & NYMA, Inc.	
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Sheet 5 of 6

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Application Number	
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Group Art Unit	
Examiner Name	
Attorney Docket Number	23404-cpa

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS

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Ramsey Patel

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Sheet	6	of	6
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Application Number

Filing Date

First Named Inventor	Bickford, Randall L.
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Group Art Unit

Examiner Name

Attorney Docket Number	23404-cpa
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**Examiner
Signature**

Ramesh Patel

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